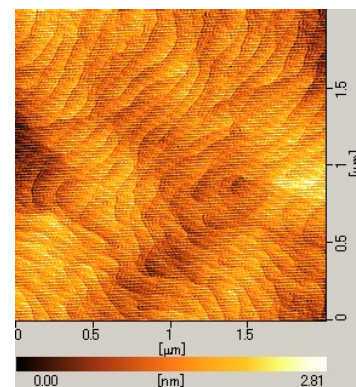


# Epitaxial Wafer Inspection Data (example)

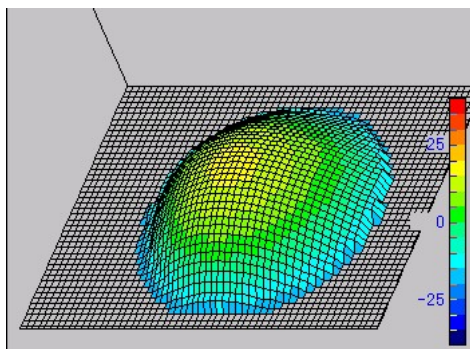
At NTT-AT, we can provide a variety of product inspection data to match whatever you need.

- Film thickness distribution
- Composition distribution
- Sheet resistivity distribution
- Mobility distribution
- AFM
- Wafer shape (SORI)
- Surface analysis (Particle inspection)
- XRD fitting
- C-V carrier density profile
- ...and others

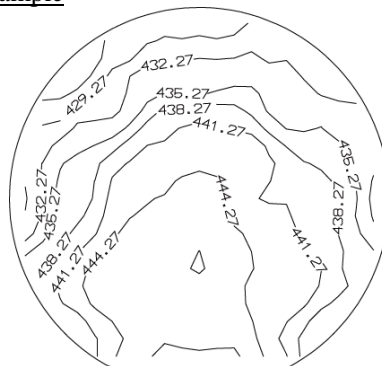
AFM observation



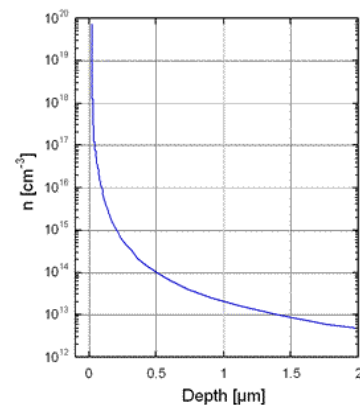
Wafer shaper measurement example



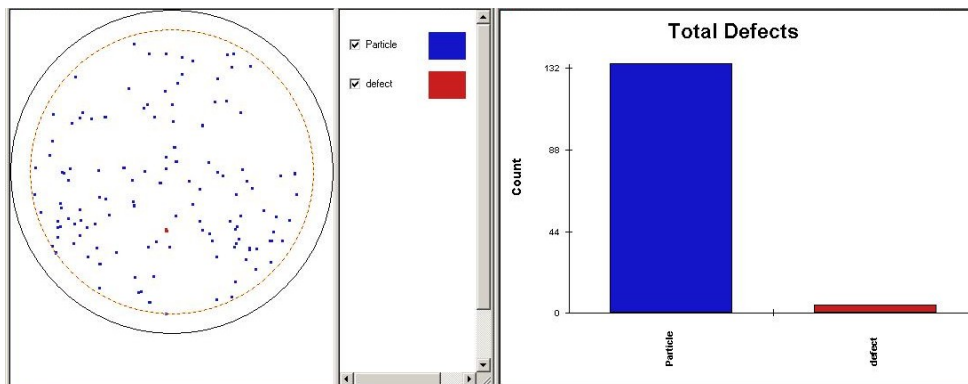
Sheet resistivity distribution measurement example



C-V carrier density profile evaluation example



Surface analysis evaluation example



※The contents of this catalogue may be changed without previous notification.

For more information:

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